

Static Characteristics
T_J = 25°C unless otherwise specified
APT29F100B2_L

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250μA	1000			V
ΔV _{BR(DSS)}/ΔT_J}	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250μA		1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance ^③	V _{GS} = 10V, I _D = 16A		0.37	0.44	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	V _{GS} = V _{DS} , I _D = 2.5mA	2.5	4	5	V
ΔV _{GS(th)}/ΔT_J}	Threshold Voltage Temperature Coefficient			-10		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 1000V V _{GS} = 0V			250 1000	μA
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dynamic Characteristics
T_J = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
g _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 16A		34		S
C _{iss}	Input Capacitance	V _{GS} = 0V, V _{DS} = 25V f = 1MHz		8500		pF
C _{rss}	Reverse Transfer Capacitance			115		
C _{oss}	Output Capacitance			715		
C _{o(cr)} ^④	Effective Output Capacitance, Charge Related	V _{GS} = 0V, V _{DS} = 0V to 667V		290		pF
C _{o(er)} ^⑤	Effective Output Capacitance, Energy Related			150		
Q _g	Total Gate Charge	V _{GS} = 0 to 10V, I _D = 16A, V _{DS} = 500V		260		nC
Q _{gs}	Gate-Source Charge			46		
Q _{gd}	Gate-Drain Charge			125		
t _{d(on)}	Turn-On Delay Time	Resistive Switching V _{DD} = 667V, I _D = 16A R _G = 2.2Ω ^⑥ , V _{GG} = 15V		39		ns
t _r	Current Rise Time			35		
t _{d(off)}	Turn-Off Delay Time			130		
t _f	Current Fall Time			33		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
I _S	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode)			30	A
I _{SM}	Pulsed Source Current (Body Diode) ^①				120	
V _{SD}	Diode Forward Voltage	I _{SD} = 16A, T _J = 25°C, V _{GS} = 0V			1.2	V
t _{rr}	Reverse Recovery Time	I _{SD} = 16A ^③ di _{SD} /dt = 100A/μs	T _J = 25°C	230	270	ns
Q _{rr}	Reverse Recovery Charge		T _J = 125°C	500	640	
			T _J = 25°C	13		μC
I _{rrm}	Reverse Recovery Current		T _J = 125°C	35		
			T _J = 25°C	11		A
T _J = 125°C	15					
dv/dt	Peak Recovery dv/dt	I _{SD} ≤ 16A, di/dt ≤ 1000A/μs, V _{DD} = 667V, T _J = 125°C			25	V/ns

① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

② Starting at T_J = 25°C, L = 14.65mH, R_G = 25Ω, I_{AS} = 16A.

③ Pulse test: Pulse Width < 380μs, duty cycle < 2%.

④ C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{oss} with V_{DS} = 67% of V_{(BR)DSS}.

⑤ C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{oss} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -2.47E-7/V_{DS}² + 4.36E-8/V_{DS} + 8.44E-11.

⑥ R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.

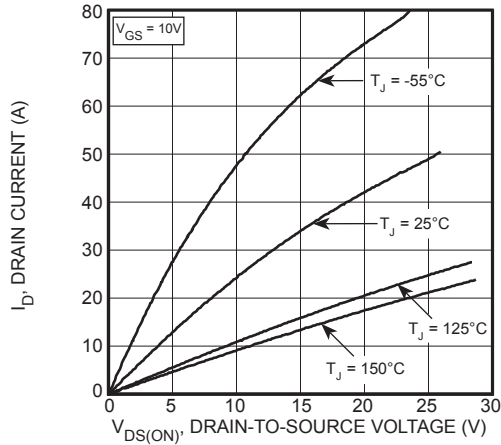


Figure 1, Output Characteristics

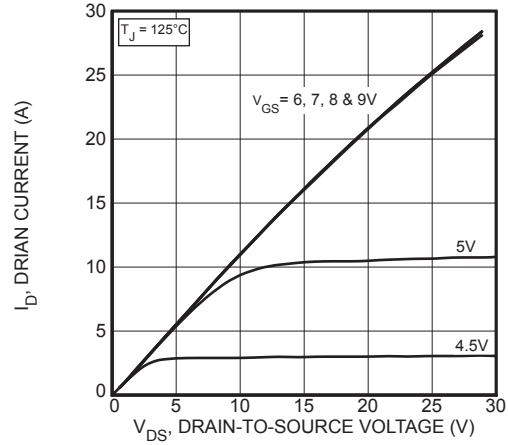


Figure 2, Output Characteristics

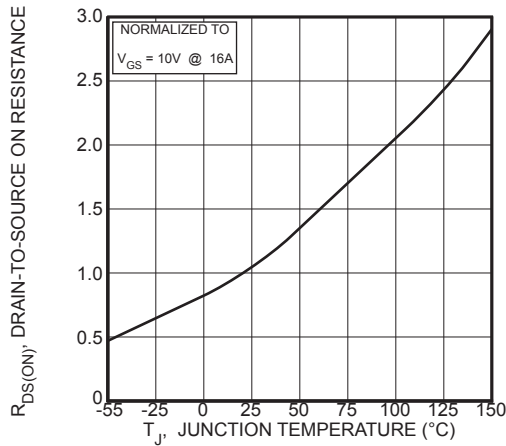


Figure 3, $R_{DS(ON)}$ vs Junction Temperature

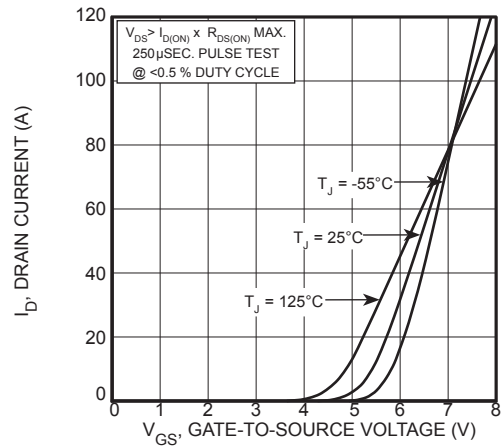


Figure 4, Transfer Characteristics

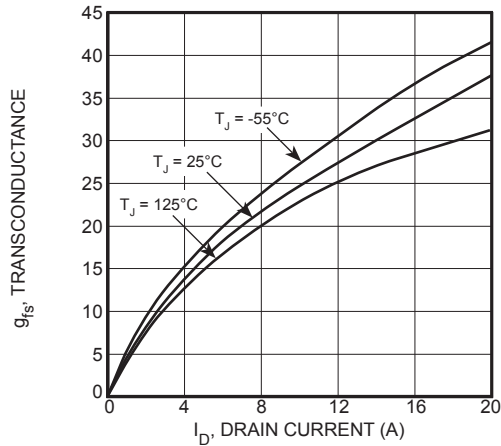


Figure 5, Gain vs Drain Current

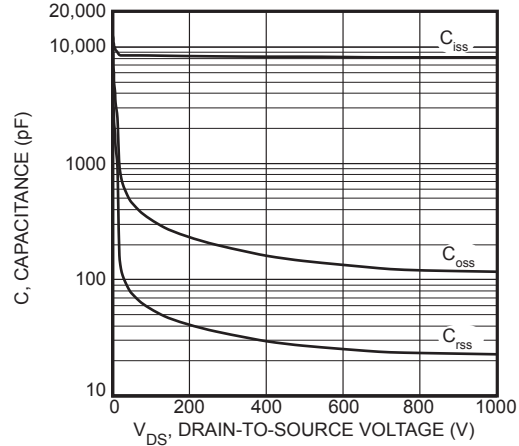


Figure 6, Capacitance vs Drain-to-Source Voltage

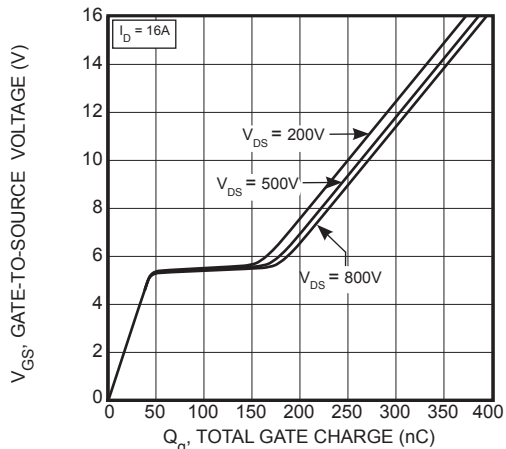


Figure 7, Gate Charge vs Gate-to-Source Voltage

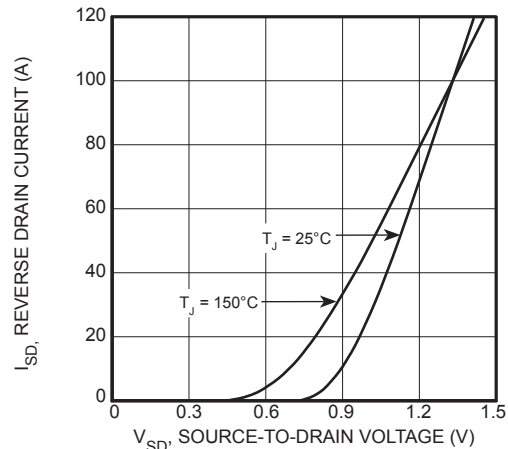
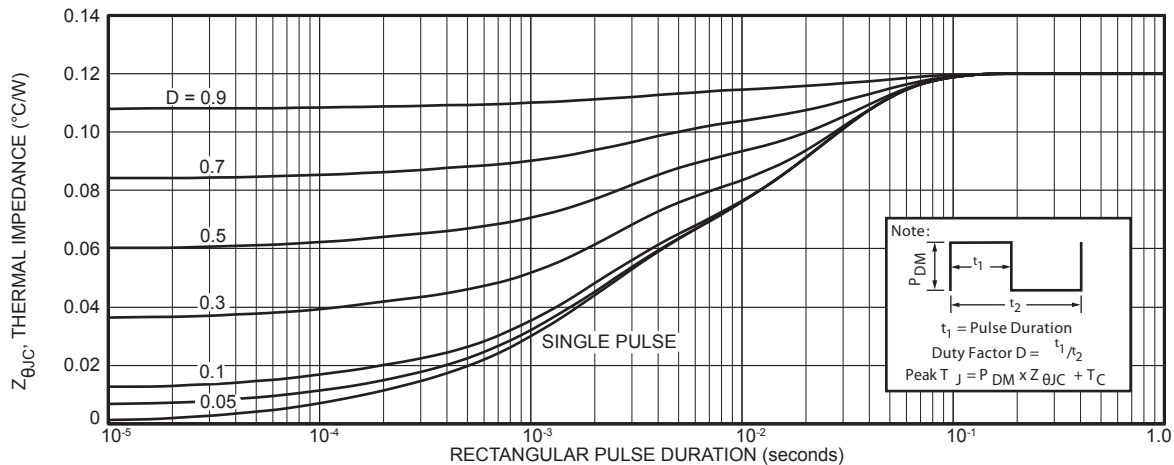
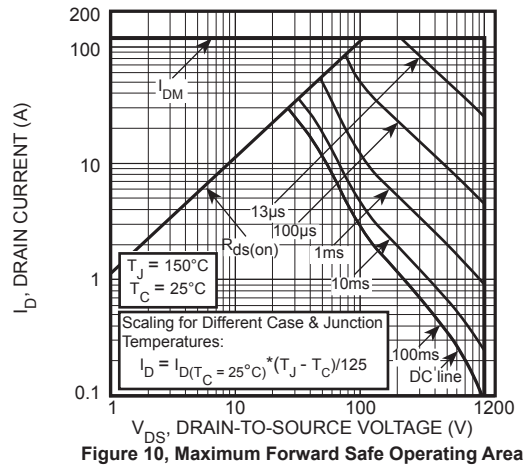
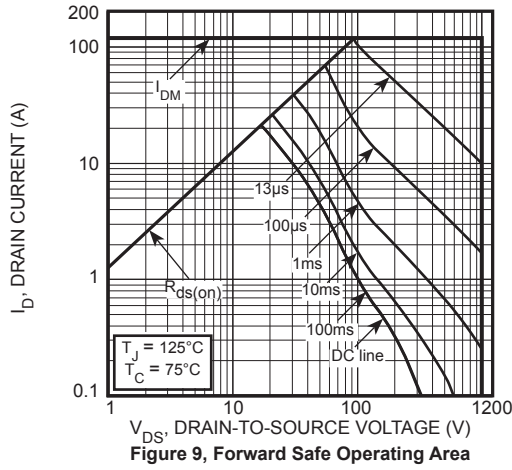
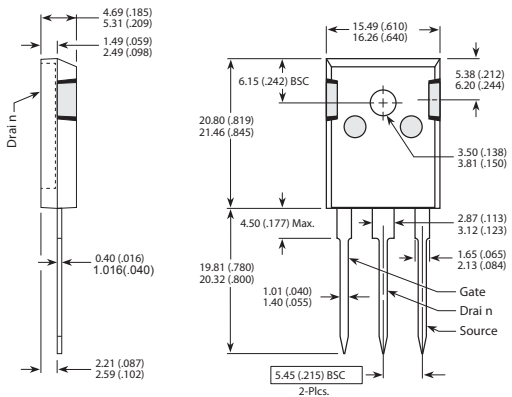


Figure 8, Reverse Drain Current vs Source-to-Drain Voltage



TO-247 (B) Package Outline

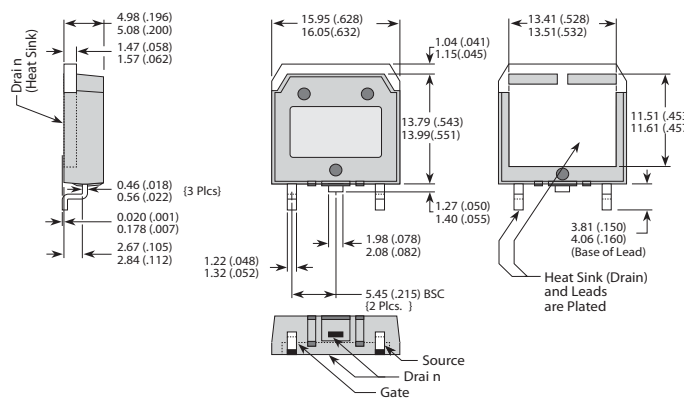
Ⓛ SAC: Tin, Silver, Copper



Dimensions in Millimeters (Inches)

D³PAK Package Outline

Ⓛ 100% Sn Plated



Dimensions in Millimeters (Inches)

Mouser Electronics

Authorized Distributor

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